AMENDMENT AND PRESENTATION OF CLAIMS

Please replace all prior claims in the present application with the following claims, in which claims 1-10 are currently amended.

1. (Currently Amended) A high-frequency High-frequency measuring system for measuring a device under test (19), comprising:

a measuring-device unit (2); and
at least one high-frequency module (3, 24, 25), wherein each high-frequency module (3, 24, 25) can be is placed spatially separately separated from the measuring-device unit (2) and each high-frequency module (3, 24, 25) can be is connected to the measuring-device unit (2) via a digital interface (23, 26, 27), wherein

characterised in that

the processing of input data to form a bitstream to be transmitted for transmission via the digital interface (26) takes place by includes assigning the symbols to states in the a state diagram of an the I-Q (in phase – quadrature phase) level in the measuring-device unit (2), or

and/or that a digitised digitized intermediate-frequency signal is transmitted via the digital interface (27).

2. (Currently Amended) A high-frequency High-frequency measuring system according to claim 1, wherein

eharacterised in-that

the <u>at least one</u> high-frequency module (3, 24, 25) comprises a transmitter device and/or or a receiver device (28, 29) for communication with a <u>the</u> device under test (19).

3. (Currently Amended) A high-frequency High-frequency measuring system according to claim 1 or 2, wherein

characterised in that

the digital interface (23, 26, 27) is a serial interface.

4. (Currently Amended) A high-frequency High-frequency measuring system according to claim 1 or 2, wherein

eharacterised in that

the digital interface (23, 26, 27) is a parallel interface.

5. (Currently Amended) A high-frequency High frequency measuring system according to claim any one of claims 1 to 4, wherein

eharacterised in that

the digital interface (23, 26, 27) is an optical interface.

6. (Currently Amended) A high-frequency High frequency measuring system according to claim any one of claims 1 to 4, wherein

characterised in that

the digital interface (23, 26, 27) is an electrical interface.

7. (Currently Amended) A high-frequency High-frequency measuring system according to claim any one of claims 1 to 6, wherein

characterised in that

the at least one high-frequency module (3, 24, 25) is supplied with electrical energy via a power-supply unit (14, 40) independent from the measuring-device unit (2).

8. (Currently Amended) A high-frequency High-frequency measuring system according to claim any one of claims 1 to 7, wherein

eharacterised-in-that

several a plurality of identical ports (5.1, 5.2, 5.3) are provided on the measuring-device unit (2) for the digital interface (23).

9. (Currently Amended) A high-frequency High-frequency measuring system according to claim any one of claims 1 to 8, wherein

eharacterised in that

several a plurality of different ports (5.1, 5.2, 5.3, 6.1, 6.2, 6.3) are provided on the measuring-device unit for the digital interface (23).

10. (Currently Amended) A high-frequency High frequency measuring system according to claim any one of claims 1 to 9, wherein

eharacterised-in-that

control data <u>or and/or</u> user data <u>is ean be</u> transmitted in a <u>standardized</u> standardised form via the digital interface, and <u>that wherein</u> the at least one high-frequency module (24') comprises means for processing a high-frequency signal with regard to the transmission of data in <u>standardized</u> standardised form via the digital interface <u>or and/or</u> for processing the data transmitted in <u>standardized</u> standardised form with regard to at least one <u>predetermined given</u> transmission standard for the high-frequency signal.